International Rectifier

- Advanced Process Technology
- Isolated Package
- High Voltage Isolation = 2.5KVRMS ⑤
- Sink to Lead Creepage Dist. = 4.8mm
- Fully Avalanche Rated
- Lead-Free

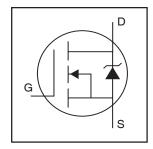
Description

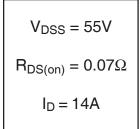
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

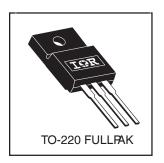
The TO-220 Fullpak eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The Fullpak is mounted to a heatsink using a single clip or by a single screw fixing

IRFIZ24NPbF

HEXFET® Power MOSFET







Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V	14	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	10	Α
I _{DM}	Pulsed Drain Current ① ©	68	
P _D @T _C = 25°C	Power Dissipation	29	W
	Linear Derating Factor	0.19	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy@6	71	mJ
I _{AR}	Avalanche Current@6	10	Α
E _{AR}	Repetitive Avalanche Energy①	2.9	mJ
dv/dt	Peak Diode Recovery dv/dt 3 6	5.0	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		5.2	00/14/
$R_{\theta JA}$	Junction-to-Ambient		65	°C/W

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Electrical Characteristics @ $T_J = 25^{\circ}C$ (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.052		V/°C	Reference to 25°C, I _D = 1mA®
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.07	Ω	V _{GS} = 10V, I _D = 7.8A ⊕
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
9 _{fs}	Forward Transconductance	4.5			S	V _{DS} = 25V, I _D = 10A [©]
I _{DSS}	Drain-to-Source Leakage Current			25	μA	$V_{DS} = 55V$, $V_{GS} = 0V$
.D22	Brain to Godroo Edunage Garrent			250	μΛ	$V_{DS} = 44V, V_{GS} = 0V, T_J = 150^{\circ}C$
lana	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100		V _{GS} = -20V
Qg	Total Gate Charge			20		I _D = 10A
Q _{gs}	Gate-to-Source Charge			5.3	nC	$V_{DS} = 44V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			7.6		V_{GS} = 10V, See Fig. 6 and 13 \oplus 6
t _{d(on)}	Turn-On Delay Time		4.9			$V_{DD} = 28V$
t _r	Rise Time		34			$I_D = 10A$
t _{d(off)}	Turn-Off Delay Time		19		ns	$R_G = 24\Omega$
t _f	Fall Time		27			$R_D = 2.6\Omega$, See Fig. 10 \oplus 6
1	Internal Drain Inductance		4.5			Between lead,
L _D	Internal Diam inductance		4.5		nH	6mm (0.25in.)
L _S	Internal Source Inductance		7.5			from package
						and center of die contact
C _{iss}	Input Capacitance		370			$V_{GS} = 0V$
C _{oss}	Output Capacitance		140		pF	$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		65		۱ ۲۰	f = 1.0MHz, See Fig. 5©
С	Drain to Sink Capacitance		12			f = 1.0MHz

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions			
Is	Continuous Source Current			14		MOSFET symbol			
	(Body Diode)			14	A	showing the			
I _{SM}	Pulsed Source Current			68	-00			1 ^	integral reverse
	(Body Diode) ① ⑥					p-n junction diode.			
V _{SD}	Diode Forward Voltage			1.3	V	T _J = 25°C, I _S = 7.8A, V _{GS} = 0V ④			
t _{rr}	Reverse Recovery Time		56	83	ns	$T_J = 25^{\circ}C$, $I_F = 10A$			
Q _{rr}	Reverse RecoveryCharge		120	180	μC	di/dt = 100A/µs ⊕ ⊚			
t _{on}	Forward Turn-On Time	Inti	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)						

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\begin{tabular}{ll} \mathbb{O} $V_{DD}=25V, starting $T_J=25^\circ$C, $L=1.0mH$ \\ $R_G=25\Omega, I_{AS}=10A.$ (See Figure 12) \\ \end{tabular}$
- $\begin{tabular}{l} @ I_{SD} \le 10A, \ di/dt \le 280A/\mu s, \ V_{DD} \le V_{(BR)DSS}, \\ T_{J} \le 175^{\circ}C \end{tabular}$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- ⑤ t=60s, f=60Hz
- © Uses IRFZ24N data and test conditions

IRFIZ24NPbF

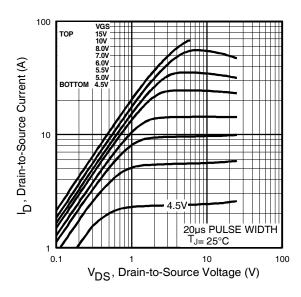


Fig 1. Typical Output Characteristics

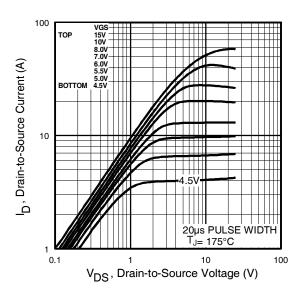


Fig 2. Typical Output Characteristics

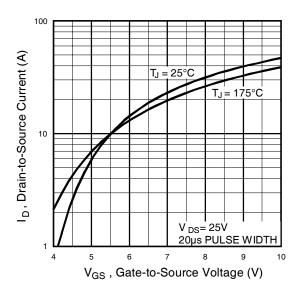


Fig 3. Typical Transfer Characteristics

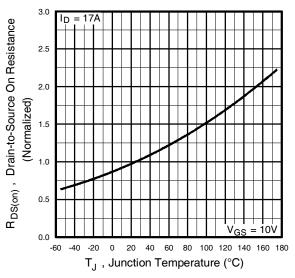


Fig 4. Normalized On-Resistance Vs. Temperature

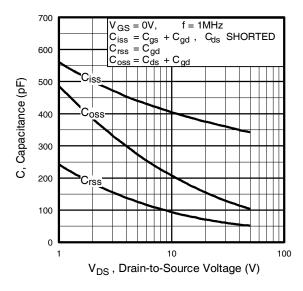


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

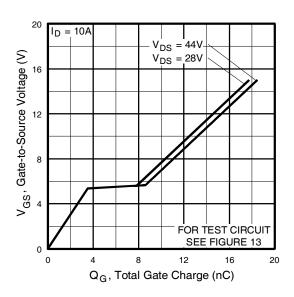


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

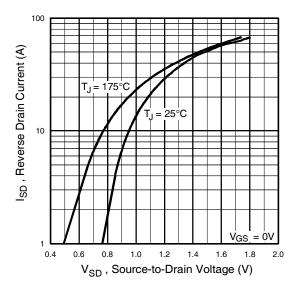


Fig 7. Typical Source-Drain Diode Forward Voltage

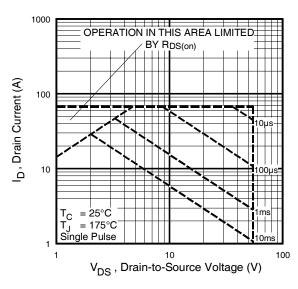


Fig 8. Maximum Safe Operating Area

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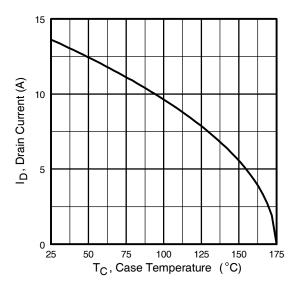


Fig 9. Maximum Drain Current Vs. Case Temperature

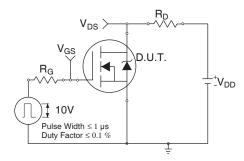


Fig 10a. Switching Time Test Circuit

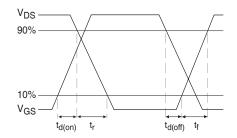


Fig 10b. Switching Time Waveforms

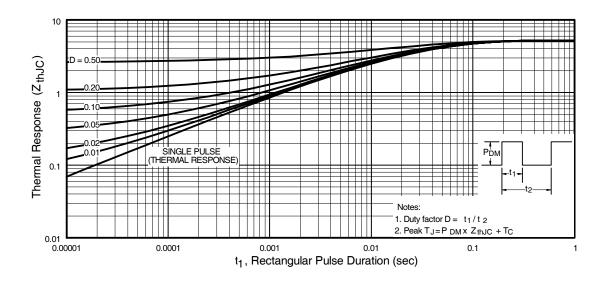


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

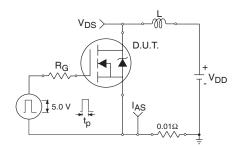


Fig 12a. Unclamped Inductive Test Circuit

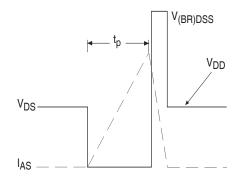


Fig 12b. Unclamped Inductive Waveforms

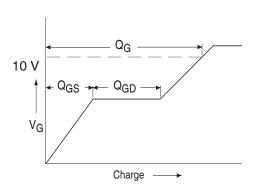


Fig 13a. Basic Gate Charge Waveform

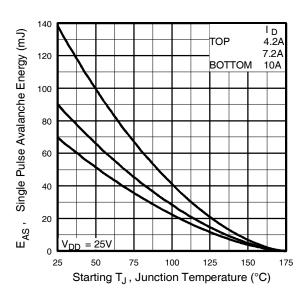


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

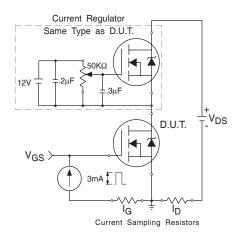
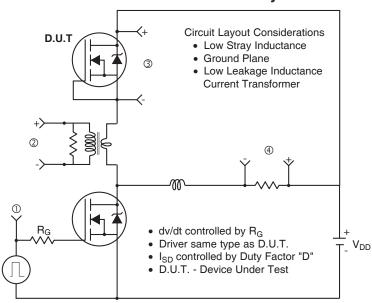
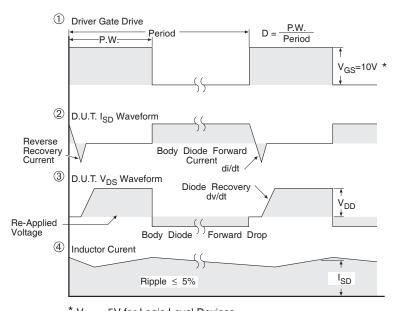


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



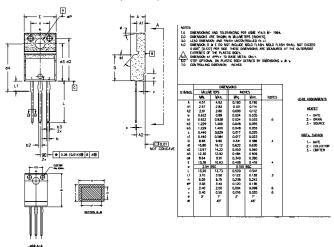


* $V_{GS} = 5V$ for Logic Level Devices

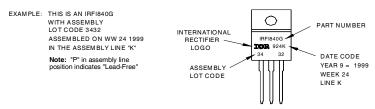
Fig 14. For N-Channel HEXFETS

TO-220 Full-Pak Package Outline

Dimensions are shown in millimeters (inches)



TO-220 Full-Pak Part Marking Information



Data and specifications subject to change without notice.



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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/